

# Test Report

ARIMA OPTOELECTRONICS CORP.

7 TH FL, NO. 349, JEN HO RD., SEC. 2, DASH, TAOYUAN,  
335 TAIWAN, R.O.C.

Report No. : CE/2005/C4270A

Date : 2005/12/22

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**The following merchandise was (were) submitted and identified by the client as :**

Type of Product : APC LASER DIODE  
Sample Received : 2005/12/15  
Testing Date : 2005/12/15 TO 2005/12/22

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**Test Result** : - Please see the next page -

  
Daniel Yeh, M.R. / Operation Manager  
Signed for and on behalf of  
SGS TAIWAN LTD.

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## Test Result

PART NAME NO.1 : MIXED ALL PARTS

Test Item (s):	Unit	Method	MDL	Result
				No.1
Monobromobiphenyl	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.
Dibromobiphenyl	%		0.0005	N.D.
Tribromobiphenyl	%		0.0005	N.D.
Tetrabromobiphenyl	%		0.0005	N.D.
Pentabromobiphenyl	%		0.0005	N.D.
Hexabromobiphenyl	%		0.0005	N.D.
Heptabromobiphenyl	%		0.0005	N.D.
Octabromobiphenyl	%		0.0005	N.D.
Nonabromobiphenyl	%		0.0005	N.D.
Decabromobiphenyl	%		0.0005	N.D.
<b>Total PBBs (Polybrominated biphenyls)/Sum of above</b>	%		-	N.D.
Monobromobiphenyl ether	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.
Dibromobiphenyl ether	%		0.0005	N.D.
Tribromobiphenyl ether	%		0.0005	N.D.
Tetrabromobiphenyl ether	%		0.0005	N.D.
Pentabromobiphenyl ether	%		0.0005	N.D.
Hexabromobiphenyl ether	%		0.0005	N.D.
Heptabromobiphenyl ether	%		0.0005	N.D.
Octabromobiphenyl ether	%		0.0005	N.D.
Nonabromobiphenyl ether	%		0.0005	N.D.
Decabromobiphenyl ether	%		0.0005	N.D.
<b>Total PBBEs(PBDEs) (Polybrominated biphenyl ethers)/Sum of above</b>	%		-	N.D.
<b>Total of Mono to Nona-brominated biphenyl ether. (Note 4)</b>	%		-	N.D.

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Test Item (s):	Unit	Method	MDL	Result
				No.1
Chromium VI (Cr+6)	ppm	UV-VIS after reference to US EPA 3060A.	2	N.D.
Cadmium (Cd)	ppm	ICP-AES after reference to EN 1122, method B:2001 or other acid digestion.	2	N.D.
Mercury (Hg)	ppm	ICP-AES after reference to US EPA 3052 or other acid digestion.	2	N.D.
Lead (Pb)	ppm	ICP-AES after reference to US EPA 3050B or other acid digestion.	2	6237.0

- NOTE: (1) N.D. = Not detected (<MDL)  
 (2) ppm = mg/kg  
 (3) MDL = Method Detection Limit  
 (4) Decabromodiphenyl ether (DecaBDE) in polymeric applications is exempted by Commission Decision of 13 Oct 2005 amending Directive 2002/95/EC notified under document 2005/717/EC.  
 (5) PBBEs=PBDEs=Polybrominated Diphenyl Ethers=PBDOs=PBBOs.  
 (6) " - " = Not Regulation

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